

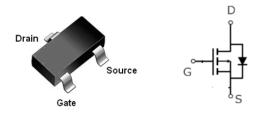
Features

- Low R_{DS(on)} @V_{GS}=-4.5V
- -3.3V Logic Level Control
- P Channel SOT23 Package
- Pb-Free, RoHS Compliant

Applications

- Charging switch for portable devices
- Small brushless DC motor drive
- Load Switch for Portable Devices
- DC-to-DC converters
- Power Management Functions

Order Information



SOT23

Product	Package	Marking	Packing	Min Unit Quantity
XPX2305AS	SOT23	A5SHB	3000PCS/Reel	3000PCS

Absolute Maximum Ratings

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

Symbol	Parameter	Rating	Unit				
Common F	Common Ratings (TA=25°C Unless Otherwise Noted)						
V _{GS}	Gate-Source Voltage	±12	V				
V _{(BR)DSS}	Drain-Source Breakdown Voltage	-20	V				
TJ	Maximum Junction Temperature	150	°C				
T _{STG}	Storage Temperature Range	-50 to 150	°C				
Mounted or	Mounted on Large Heat Sink						
I _{DM}	Pulse Drain Current Tested (1)	-16.8	А				
I _D	Continuous Drain Current	T _A =25°C	-5.2	•			
	Continuous Drain Current	T _A =70°C	-3.8	A			
D	Maximum Davias Discinction	T _A =25°C	1.25	w			
P _D	Maximum Power Dissipation	T _A =70°C	1	vv			
$R_{ hetaJA}$	Thermal Resistance Junction-Ambient	100	°C/W				



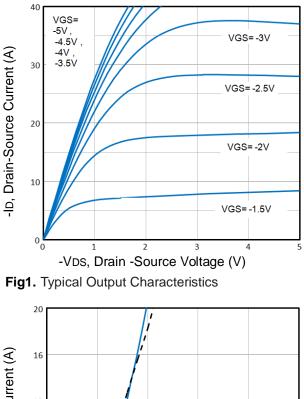
Symbol	Parameter	Condition	Min	Тур	Max	Unit	
Static Electrical Characteristics @ TJ = 25°C (unless otherwise stated)							
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	Vgs=0V Id=-250µA	-20			V	
	Zero Gate Voltage Drain Current(T_=25 $^\circ\!\!\!\mathrm{C})$	Vds=-20V, Vgs=0V			-1	μA	
DSS	Zero Gate Voltage Drain Current(T₄=125℃)	VDS=-16V, VGS=0V			-100	μA	
I _{GSS}	Gate-Body Leakage Current	Vgs=±10V, Vds=0V			±100	nA	
$V_{GS(TH)}$	Gate Threshold Voltage	Vds=Vgs, Id=-250µA	-0.4	-0.7	-1.0	V	
$R_{DS(ON)}$	Drain-Source On-State Resistance2	Vgs=-4.5V, Id=-4A		29	38	mΩ	
$R_{DS(ON)}$	Drain-Source On-State Resistance②	Vgs=-3.3V, Id=-3A		35	42	mΩ	
$R_{DS(ON)}$	Drain-Source On-State Resistance②	Vgs=-2.5V, Id=-2A		45	60	mΩ	
Dynamic Electrical Characteristics @ TJ = 25°C (unless otherwise stated)							
C _{iss}	Input Capacitance			760		pF	
C _{oss}	Output Capacitance	VDS=-10V, VGS=0V, f=1MHz		94		pF	
C _{rss}	Reverse Transfer Capacitance			76		pF	
R _g	Gate Resistance	f=1MHz		16		Ω	
Q_{g}	Total Gate Charge	. Vds=-10V		7.6		nC	
Q_{gs}	Gate Source Charge	ID=-3A,		0.9		nC	
Q_{gd}	Gate Drain Charge	Vgs=-4.5V		1.8		nC	
Switching	Characteristics						
t _{d(on)}	Turn on Delay Time			5.5		ns	
t _r	Turn on Rise Time	Vdd=-10V, Id=-2A,		3.9		ns	
t _{d(off)}	Turn Off Delay Time	Rg=3.3Ω, Vgs=-4.5V	-	11.3		ns	
t _f	Turn Off Fall Time	v 65–0 v		36		ns	
Source Dr	Source Drain Diode Characteristics						
I _{SD}	Source drain current(Body Diode)	Ta=25℃			-2	A	
V _{SD}	Forward on voltage 2	Tj=25℃, IsD=-4A, Vgs=0V		-0.87	-1.2	V	

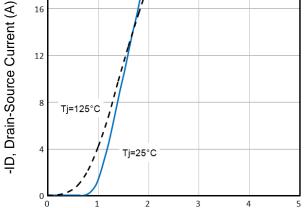
Notes:

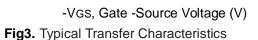
1 Pulse width limited by maximum allowable $% \sub{M}{M}$ junction temperature

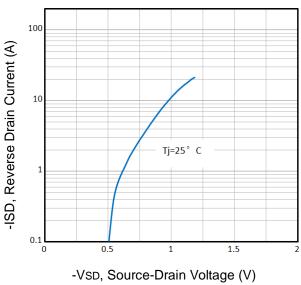


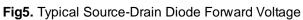
Typical Characteristics











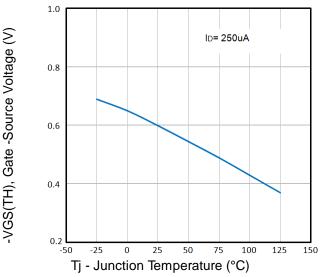
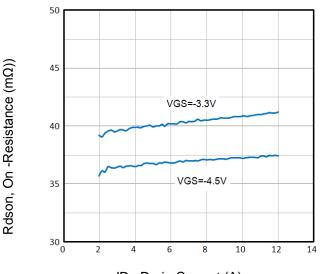


Fig2. Normalized Threshold Voltage Vs. Temperature



-ID , Drain Current (A) Fig4. On-Resistance vs. Drain Current and Gate Voltage

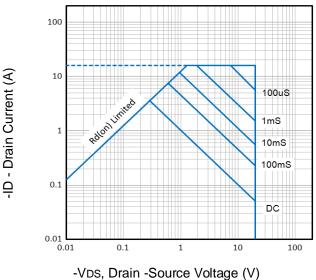
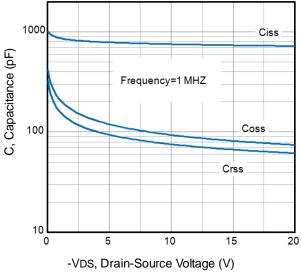


Fig6. Maximum Safe Operating Area



Typical Characteristics



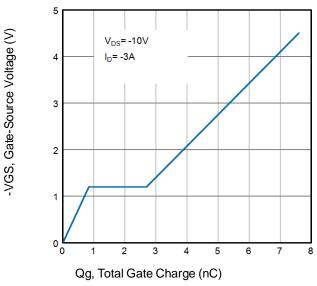


Fig7. Typical Capacitance Vs. Drain-Source Voltage

Fig8. Typical Gate Charge Vs. Gate-Source Voltage

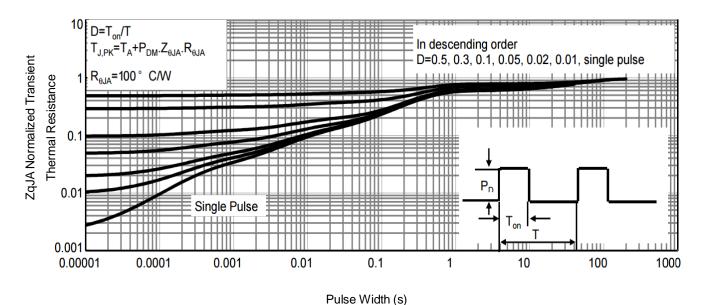


Fig9. Normalized Maximum Transient Thermal Impedance

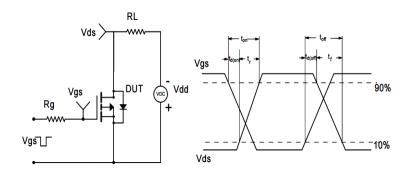


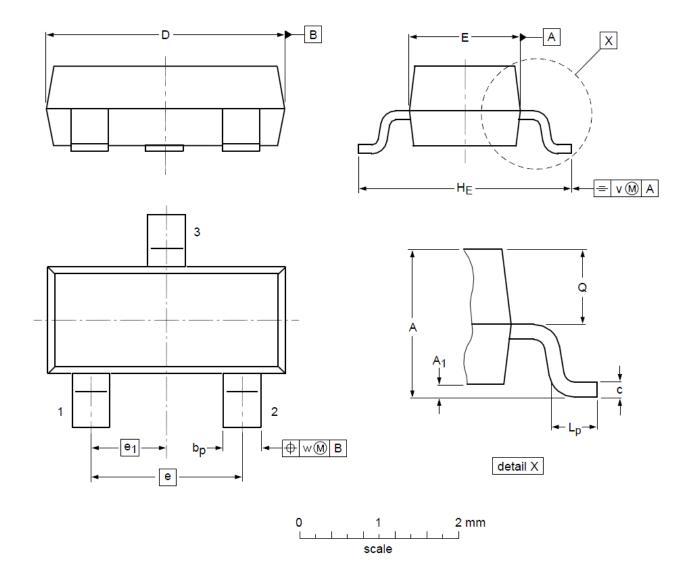
Fig10. Switching Time Test Circuit and waveforms



http://www.xpxbdt.com

P-Channel Enhancement Mode Power MOSFET

SOT23 Mechanical Data



DIMENSIONS	DIMENSIONS (unit : mm)						
Symbol	Min	Тур	Max	Symbol	Min	Тур	Max
Α	0.90	1.01	1.15	A ₁	0.01	0.05	0.10
b _p	0.30	0.42	0.50	С	0.08	0.13	0.15
D	2.80	2.92	3.00	E	1.20	1.33	1.40
е		1.90		e ₁		0.95	
H _E	2.25	2.40	2.55	L _p	0.30	0.42	0.50
Q	0.45	0.49	0.55	v		0.20	
w		0.10					



Flow (wave) soldering (solder dipping)

Product	Peak Temperature	Dipping Time
Pb device	245℃ ±5 ℃	5sec±1sec
Pb-Free device	260 ℃ +0/-5 ℃	5sec±1sec



This integrated circuit can be damaged by ESD UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

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